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b. Applicant(s)	g. Disclaimer	I. Print Fig.	q. PTOL-85b
c. Continuing Data	h. Microfiche Appendix	m. Searched Column	r. Abstract
d. PCT	i. Title	n. PTO-270/328	s. Sheets/Figs
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Sheet 1 of 1 sheet(s) Docket No. Serial No. U.S. Department of Commerce, Patent and Trademark Office AMAT/6392/DSM/LO 10/010.950 (PTO Form 1449 modified) W K/JW SUPPLEMENTAL INFORMATION DISCLOSURER RATEMENT BY **Applicant** Confirmation No.: **APPLICANT** Xia, et al. 5694 net 0 6 2003 Filing Date Group (Use several sheets if necessary) November 13, 2001 2818 Examiner Dung Anh Le **U.S. Patent Documents** Subclass Filing Date If Applicant(s) Class Document Issue *Examiner Appropriate Name Initial Number Date 780 06/29/1998 438 11/14/2000 Grill, et al. A1 6,147,009 438 623 02/11/1998 04/25/2000 Yau, et al. **A2** 6,054,379 **A3** A4 **A5** A6 **A7 A8 A9** A10 A11 A12 A13 **Foreign Patent Documents** Country Class Subclass Translation Document Date *Examiner Number Initial YES NO 冈 EP H01L 21/316 П 1 107 303 06/13/2001 **B1** C23C \Box \boxtimes WO 08/29/1999 **B**2 99/41423 **B3** OTHER ART Including Author, Title, Date, Pertinent Pages, Etc. *Examiner Initial PCT International Search Report for US/02/36229 dated 09/03/2003 (AMAT/6392.PC) C1 C2 **C3 Date Considered** Examiner *EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through

citation if not in conformance and not considered. Include copy of this form with your communication to applicant.

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